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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

JC542 U.S. PTO  
09/047944  
03/25/90

Applicant: Moshe Finarov  
Assignee: Nova Measuring Instruments, Ltd.  
Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING POLISHING  
Serial No.: Unknown Filed: Herewith  
Examiner: Unknown Group Art Unit: Unknown  
Docket No.: M-3417-1C US

San Jose, California  
March 25, 1998

ASSISTANT COMMISSIONER FOR PATENTS  
BOX PATENT APPLICATION  
Washington, D. C. 20231

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, Applicant brings the following documents to the Examiner's attention in the above-captioned application.

1. USP 4,793,895 issued 12/27/88 to Kaanta et al.
2. USP 5,157,877 issued 10/27/92 to Hashimoto
3. USP 5,240,552 issued 08/31/93 to Yu et al.
4. USP 5,337,015 issued 08/09/94 to Lustig et al.
5. USP 5,492,594 issued 02/20/96 to Burke et al.
6. USP 5,433,651 issued 07/18/95 to Lustig et al.
7. USP 5,125,740 issued 06/30/92 to Sato et al.
8. USP 5,081,796 issued 01/21/92 to Schultz
9. USP 5,081,421 issued 01/14/92 to Miller et al.
10. USP 4,018,638 issued 04/19/77 to Singer et al.

A PTO form 1449 listing these documents is enclosed.

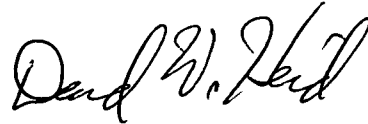
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Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made, other than as described above; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

Respectfully submitted,



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